

Instrumentation for nuclear physics experiments: **Silicon Carbide** detectors

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INFN - Laboratori Nazionali del Sud

On behalf of SiCILIA collaboration

INFN-LNF Frascati, Roma, Italy, December 4-6, 2024

Outline

- ✓ Why **Si**licon **C**arbide for radiation detection
- ✓ INFN activity on SiC detectors: **SiC**ILIA
- ✓ Main **SiC**ILIA results
- ✓ Devices performance overview
- ✓ R&D of new set-up
- ✓ Perspectives for new devices



Why Silicon Carbide for radiation detection

Property	Si	Diamond	Diamond	4H SiC
Material	MCz, FZ, epi	Polycrystal	single crystal	epitaxial
E_g [eV]	1.12	5.5	5.5	3.3
$E_{breakdown}$ [V/cm]	$3 \cdot 10^5$	10^7	10^7	$2.2 \cdot 10^6$
μ_e [cm^2/Vs]	1450	1800	>1800	800
μ_h [cm^2/Vs]	450	1200	>1200	115
v_{sat} [cm/s]	$0.8 \cdot 10^7$	$2.2 \cdot 10^7$	$2.2 \cdot 10^7$	$2 \cdot 10^7$
Z	14	6	6	14/6
ϵ_r	11.9	5.7	5.7	9.7
e-h energy [eV]	3.6	13	13	7.6
Density [g/cm ³]	2.33	3.515	3.515	3.22
Displacem. [eV]	13-20	43	43	25
e-h/ μm for mips	~80	36	36	55

- **Wide band-gap (3.3 eV)**
 - ⇒ Low Leakage current
 - ⇒ Insensitivity to the electromagnetic radiation in the visible range

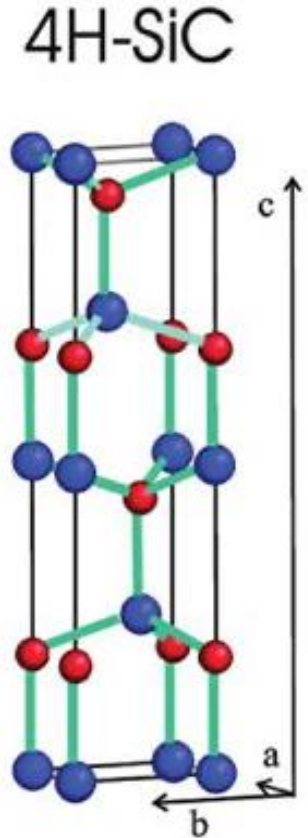
- **High Breakdown**
 - ⇒ Electrically robust devices
 - ⇒ Radiations hardness

- **Different e-h mobility**
 - ⇒ Charge Identification - pulse shape analysis

- **Fast devices**
 - ⇒ Timing applications

- **Higher displacement threshold**
 - ⇒ **Radiation hardness** more than Silicon

- **Signals amplitude**
 - ⇒ Less charge than Si, $SiC \approx Si/2$
 - ⇒ A problem for MIP!
 - ⇒ No problem in all other case



Applications

- UV - Soft-X detection
- Charged Particle detection and identification
- Neutron detection

Rad Hard devices!

2017 - INFN call CSN5 - SiCILIA

Silicon Carbide Detectors for Intense Luminosity Investigations and Applications

SiCILIA strategy



Aims

Epitaxial growth SiC beyond the state of the art ($\sim 30 \mu\text{m} \rightarrow 100 \mu\text{m}$)

Processing \Rightarrow from Schottky \rightarrow to p-n junctions

SiCILIA collaboration

INFN

CNR-IMM – Catania

CNR-INO – Pisa

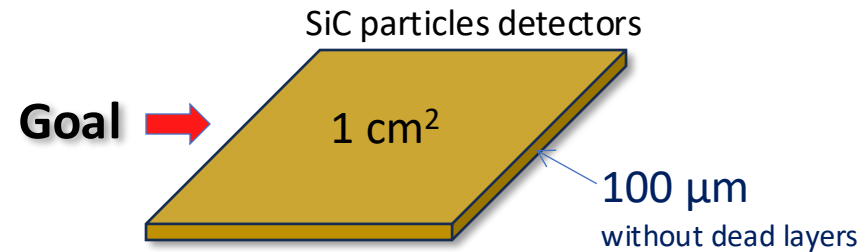
PSI – Switzerland

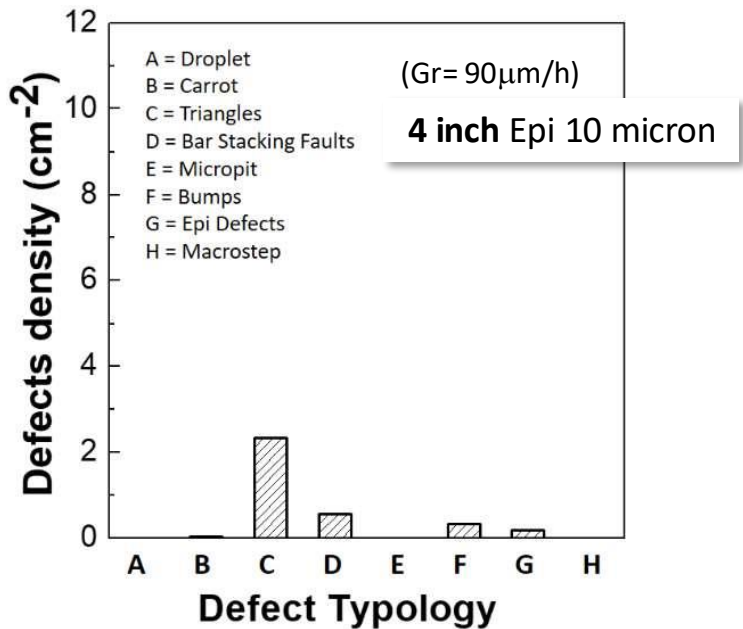
ENEA- Frascati

Fondazione Bruno Kessler (FBK) – Trento

ST Microelectronics – Catania

LPE – Catania (LPE)





Macroscopic defects

- polytype inclusions
- micropipes
- comets, carrots

Extended defects

Microscopic defects

- dislocations
- stacking faults
- interstitial, vacancies
- divacancies, antisites

Point and Point-like defects

Micro-pipe

polytype inclusions

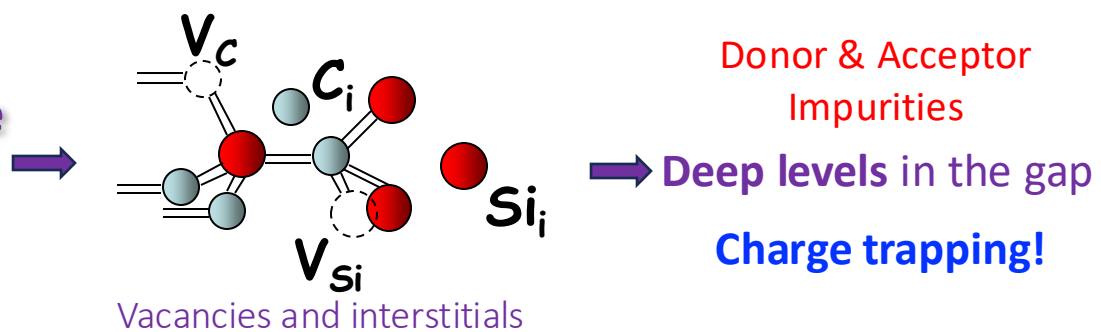
3C-SiC on 4H-SiC

100 μm

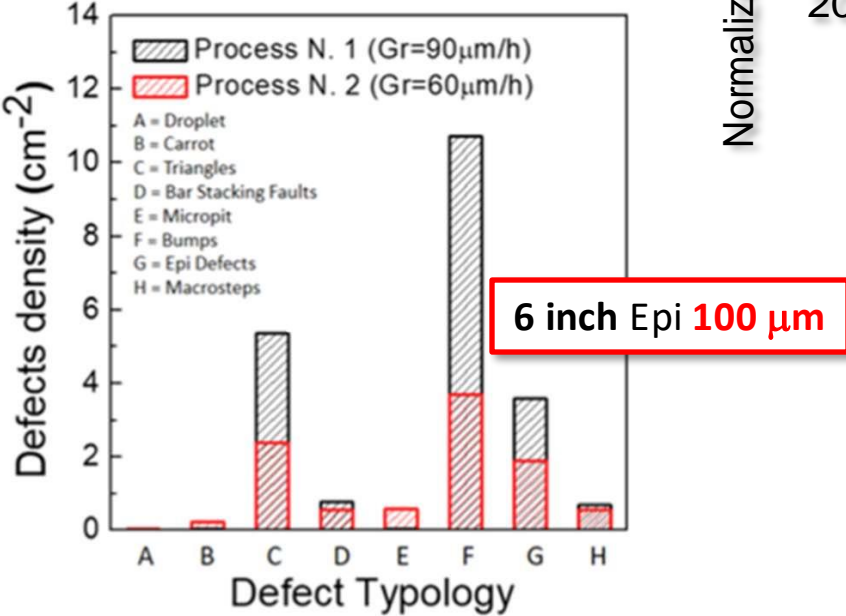
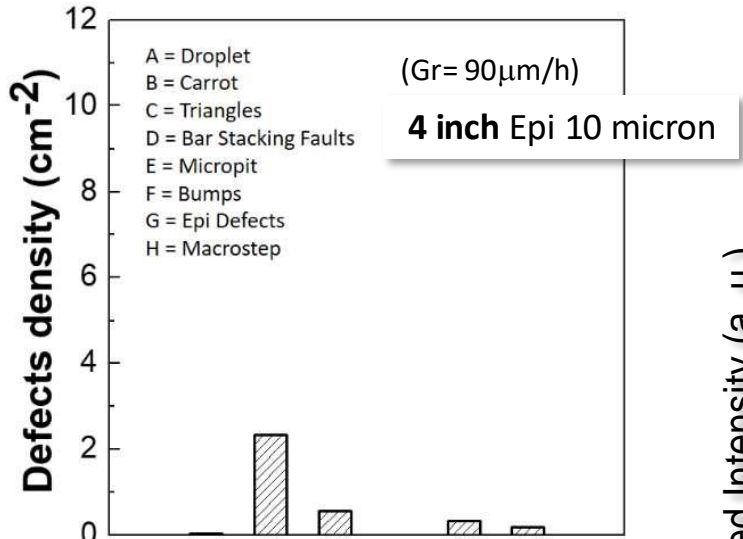
dislocations

5 nm

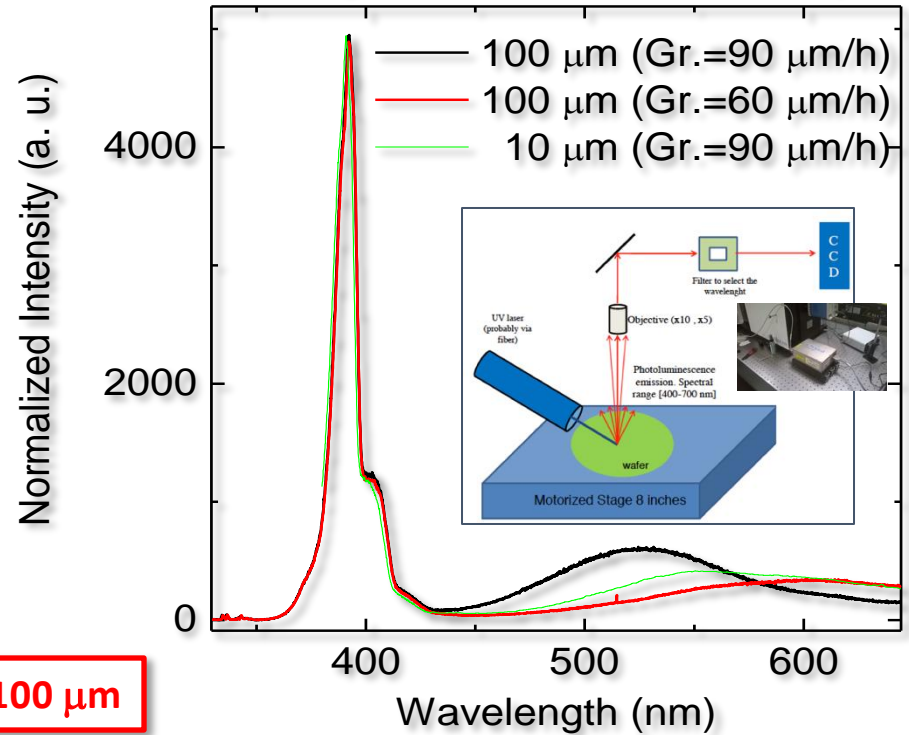
Stacking Fault



SiCILIA results: Epitaxial growths



Micro-photoluminescence analysis



Epi layer N-8 10¹³

6 inch Epi 100 µm

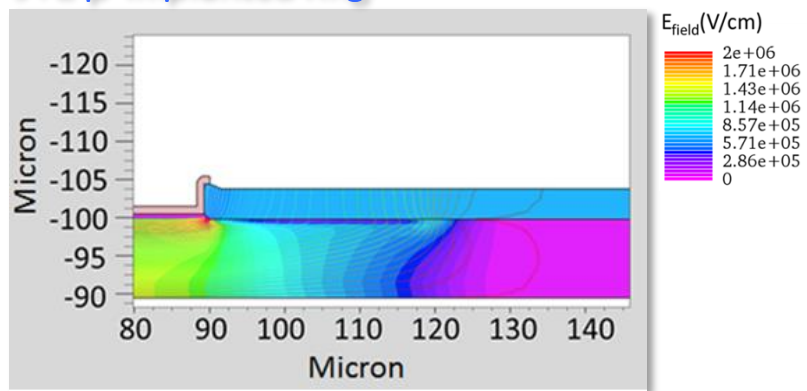
today

Epi layer N-8 10¹³

4 inch Epi 250 µm

Epi 100 µm => 300 µm is possible!

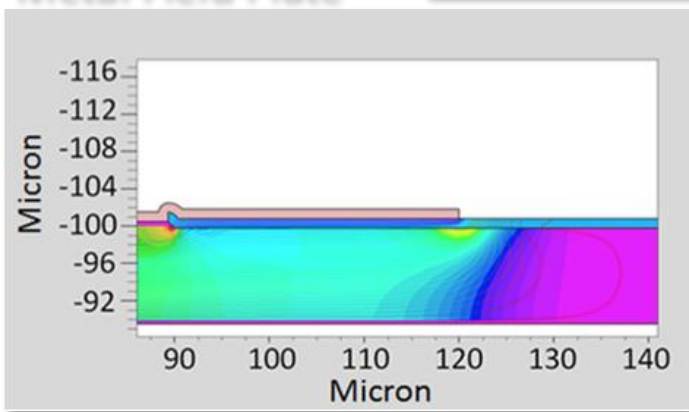
JTE p⁻ implanted ring



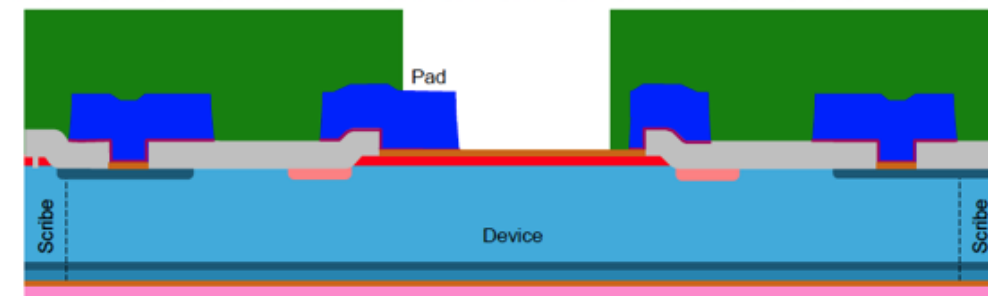
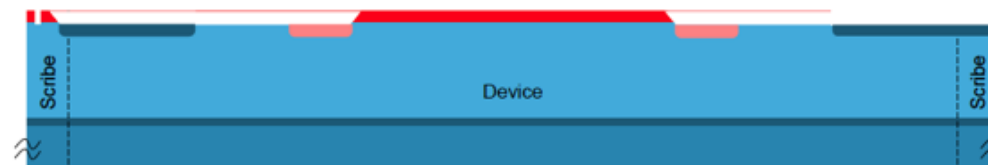
Breakdown ≥ 1.5 kV



Metal Field Plate

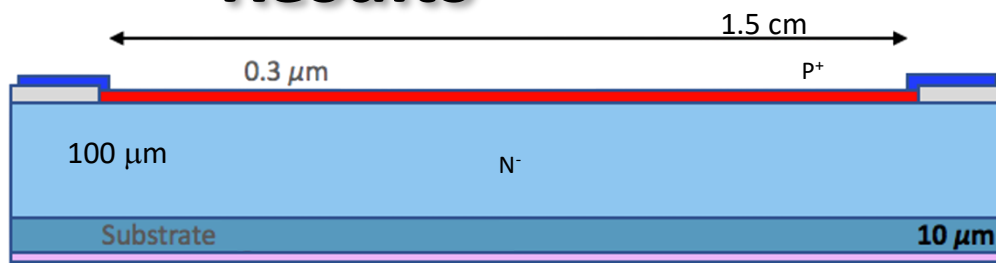


p-n diodes



Effecincy 30%

Results



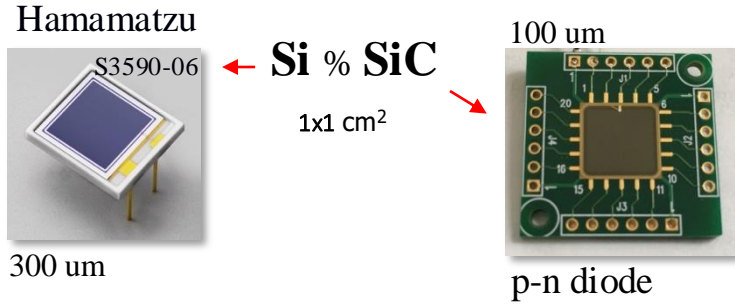
Large area
1.5x1.5 cm²



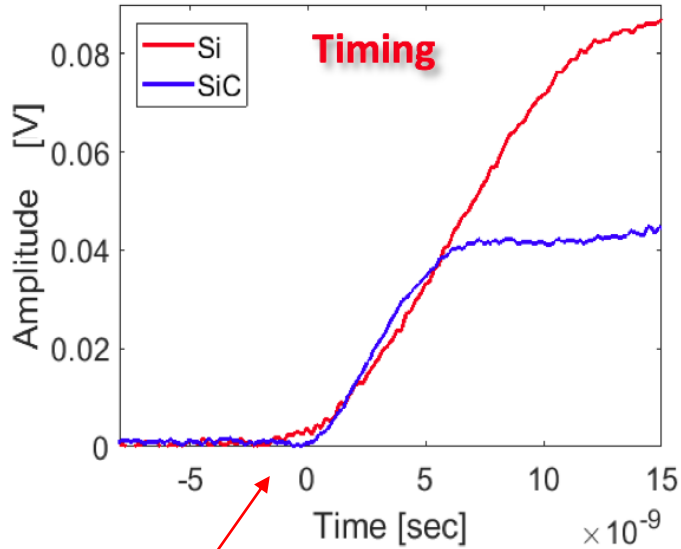
New p-n junction devices

Performance overview: Energy Resolution

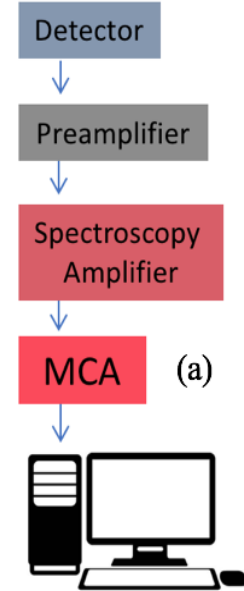
p-n diodes



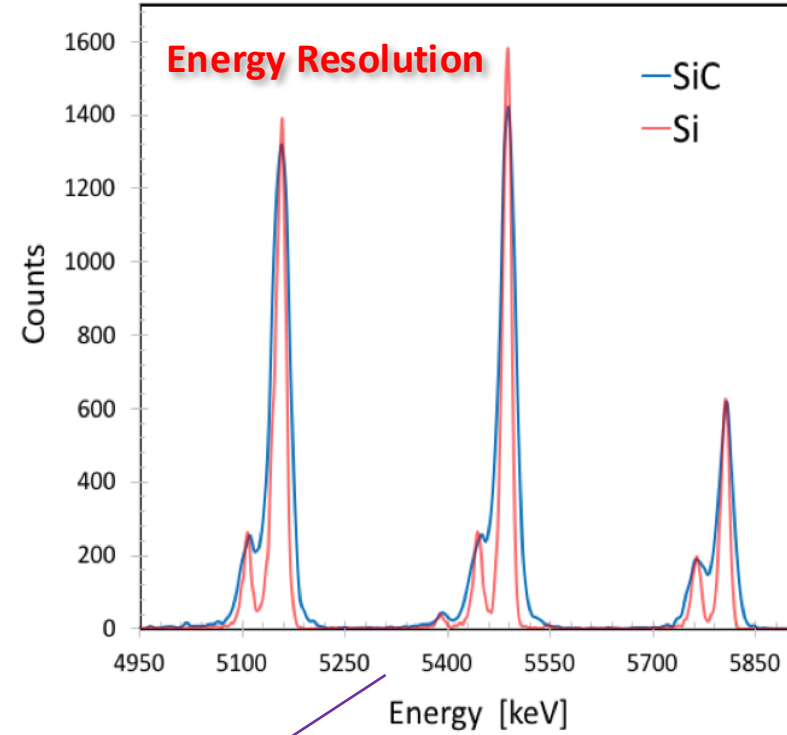
Test with radioactive ²⁴¹Am Alpha source



SiC ~ Preamp limit!



Test with radioactive ²⁴¹Am Alpha source



SiC → $FWHM_{exp} = 42.8 \text{ keV (0.4\%)}$
Si → $FWHM_{exp} = 21.4 \text{ keV (0.22\%)}$

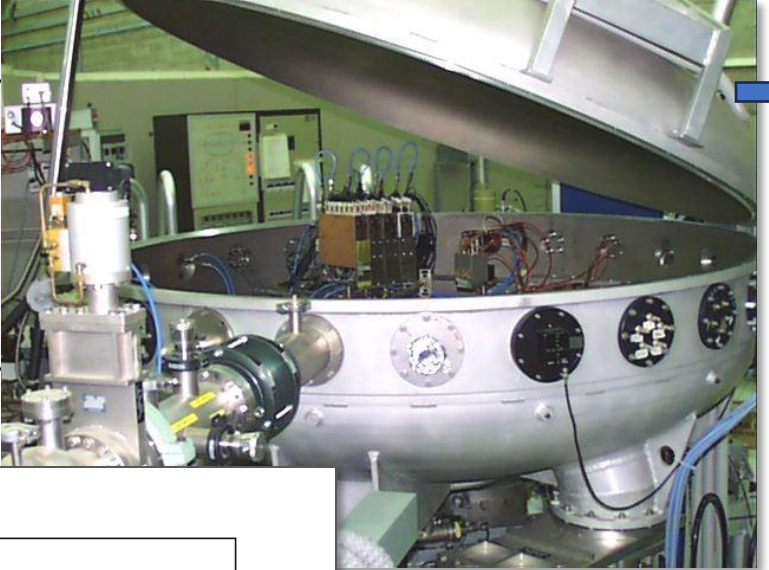
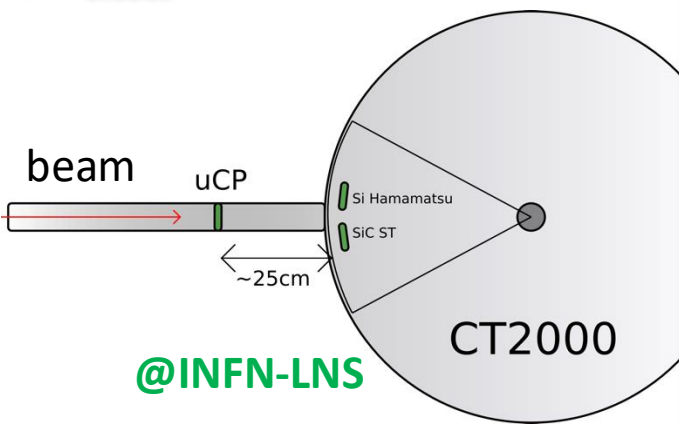
$FWHM_{exp}^2 = FWHM_{det}^2 + FWHM_{Ele}^2$ ← Electronic Noise

Si=7.3 keV **SiC=10.3 keV**

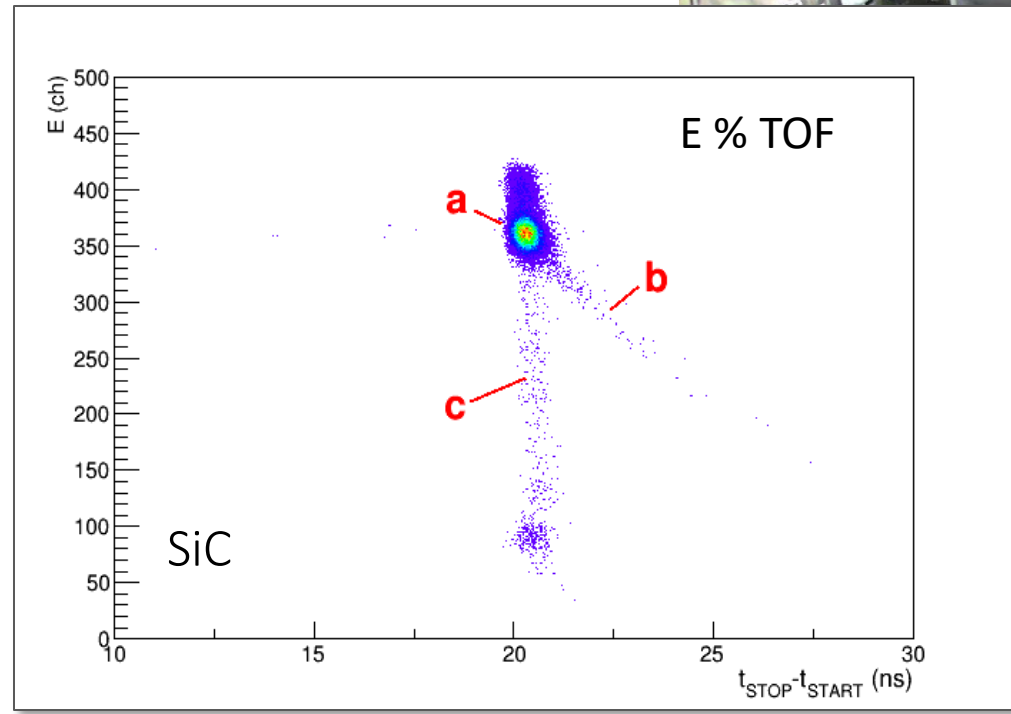


Performance overview: SiC-Timing

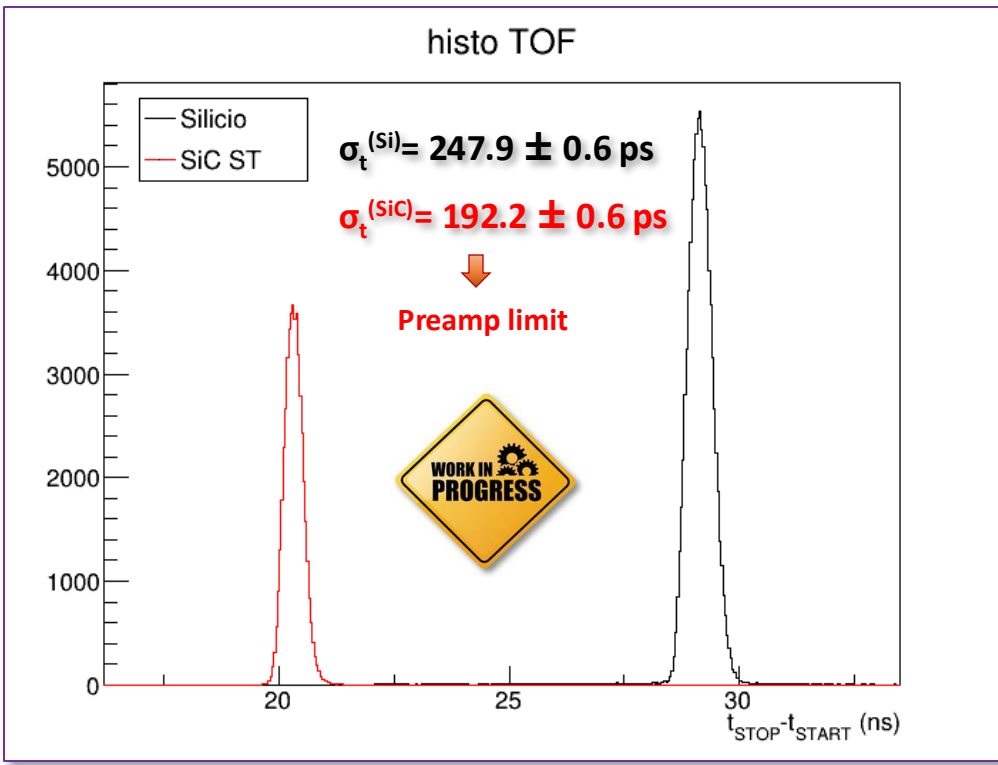
p-n diodes



- Beam ^{58}Ni @ 60MeV, 70MeV
- Digitizer CAEN DT5751
- START: μCP , STOP: Si Hamamatsu o SiC STM

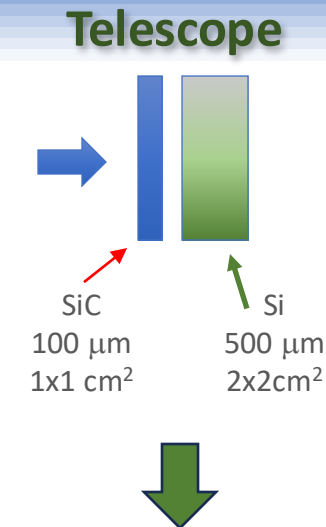
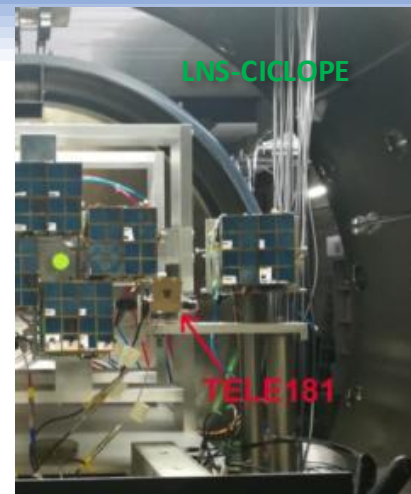
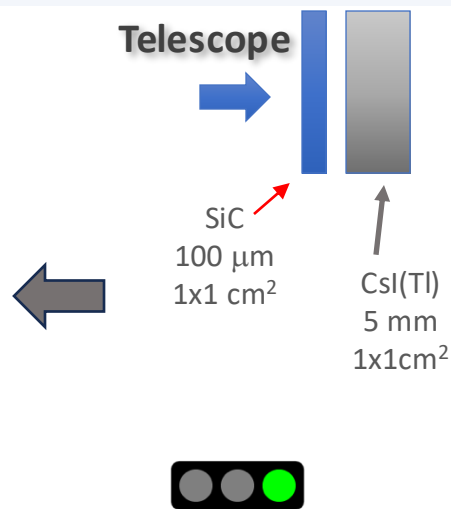
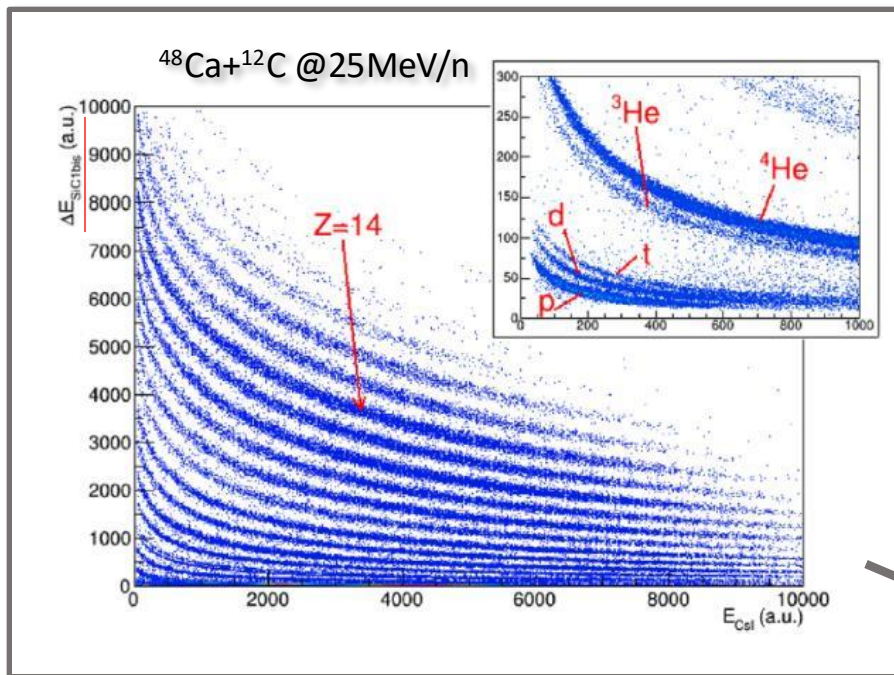


- a:** good events
- b:** μCP -wires contribution
- c:** SiC edge effects SiC



New beam test are in preparation

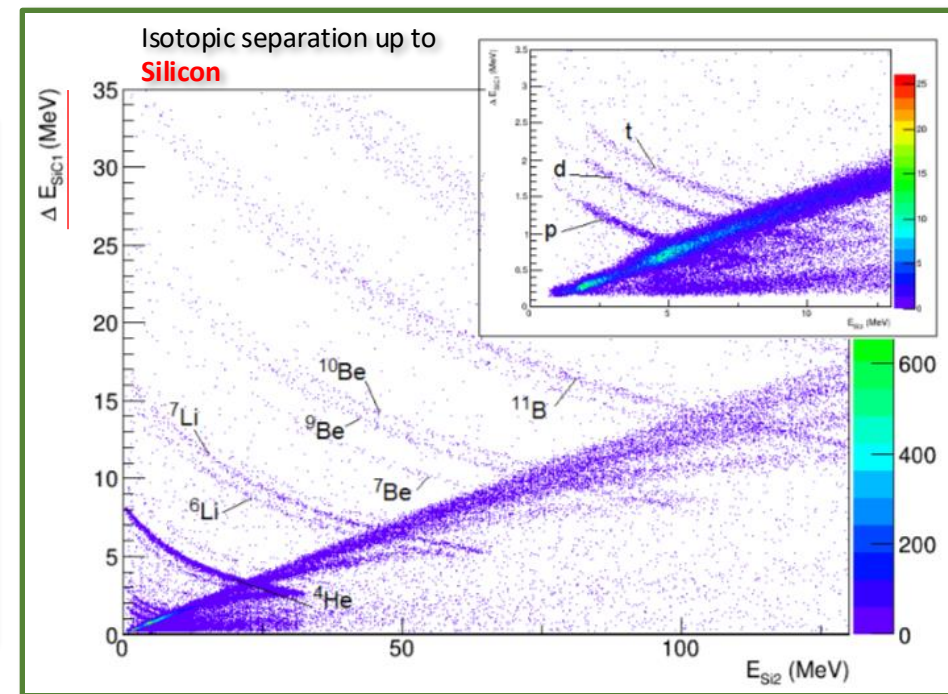
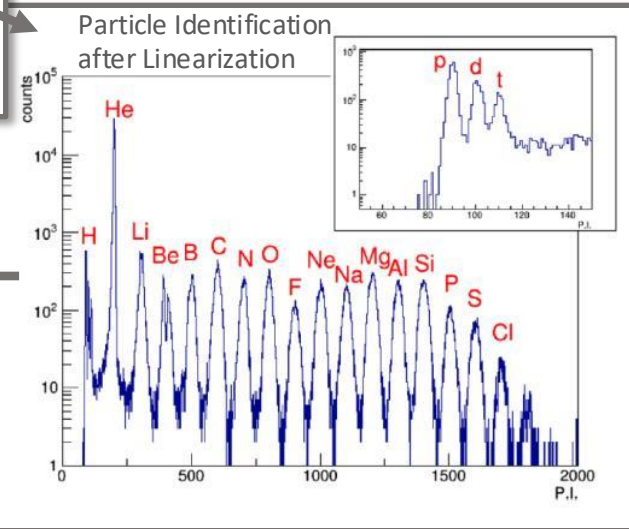
Performance overview : particles identification



Isotopes	FoM	Elements	FoM	Elements	FoM
p-d	1.4	B-C	1.9	Na-Mg	1.6
d-t	1.1	C-N	1.9	Mg-Al	1.5
^7Be - ^9Be	0.7	N-O	1.9	Al-Si	1.5
		O-F	1.8	Si-P	1.6
		F-Ne	1.6	P-S	1.5
		Ne-Na	1.6	S-Cl	1.6

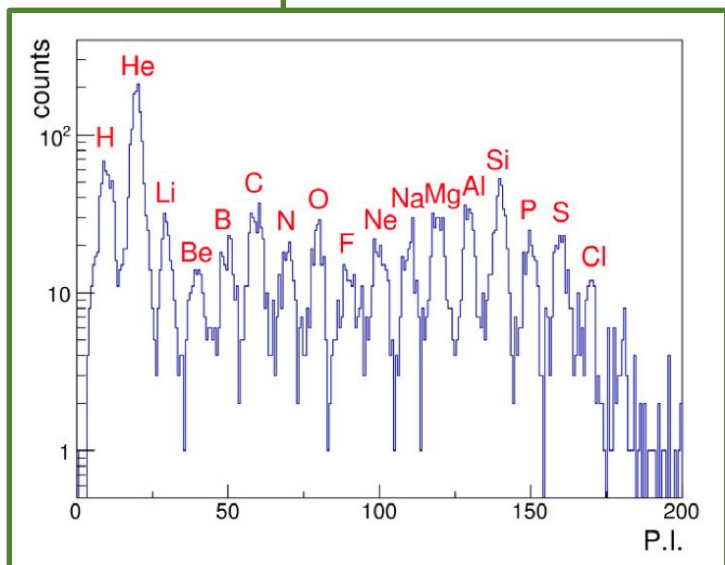
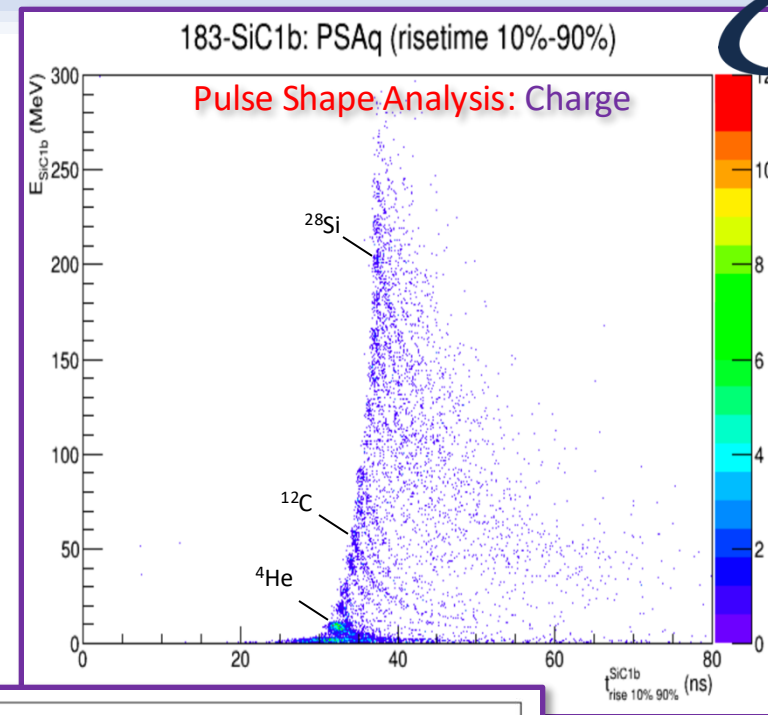
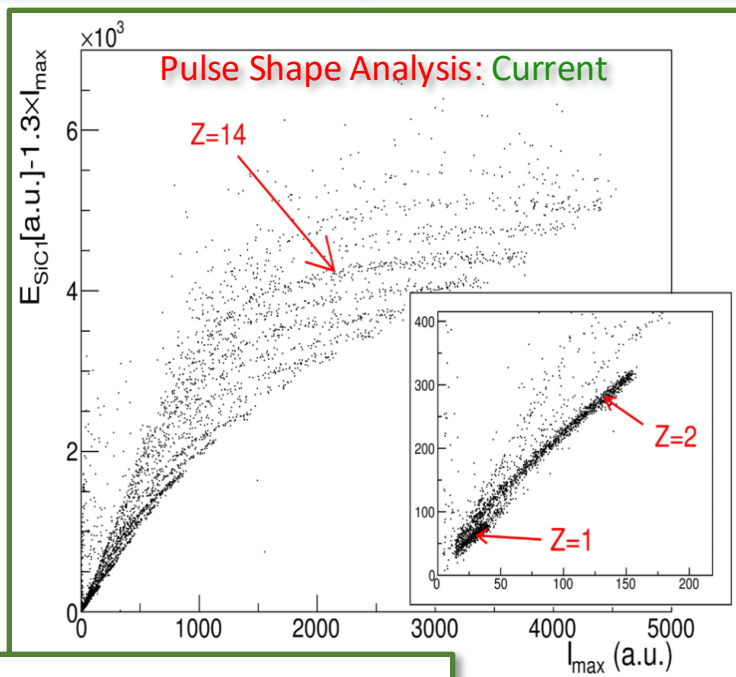
$$\text{Figure of Merit: } FoM = \frac{|PI_2 - PI_1|}{(FWHM_2 + FWHM_1)}$$

good separation if $FoM > 0.7$

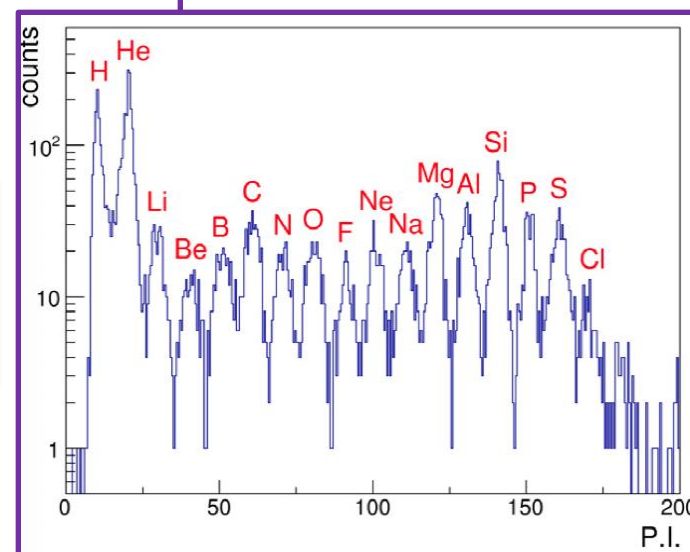


Performance overview : particles identification

Pulse Shape Analysis

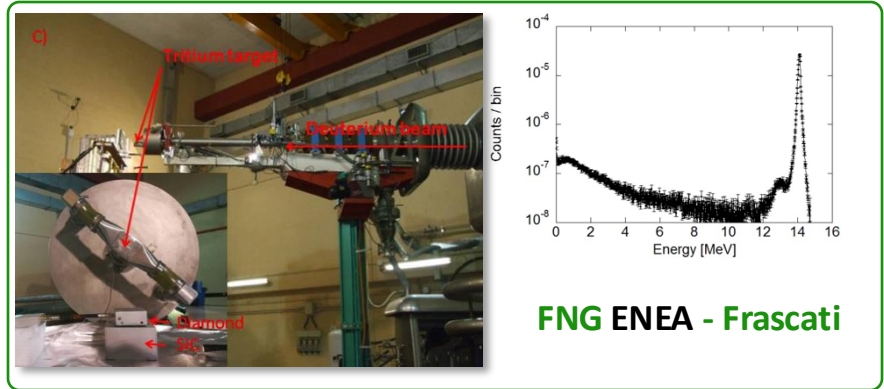


Pair	FoM	Pair	FoM
H-He	5.1	F-Ne	1.0
He-Li	3.1	Ne-Na	1.2
Li-Be	1.7	Na-Mg	1.2
Be-B	1.4	Mg-Al	1.2
B-C	1.3	Al-Si	1.3
C-N	1.3	Si-P	1.4
N-O	1.4	P-S	1.2
O-F	1.1		

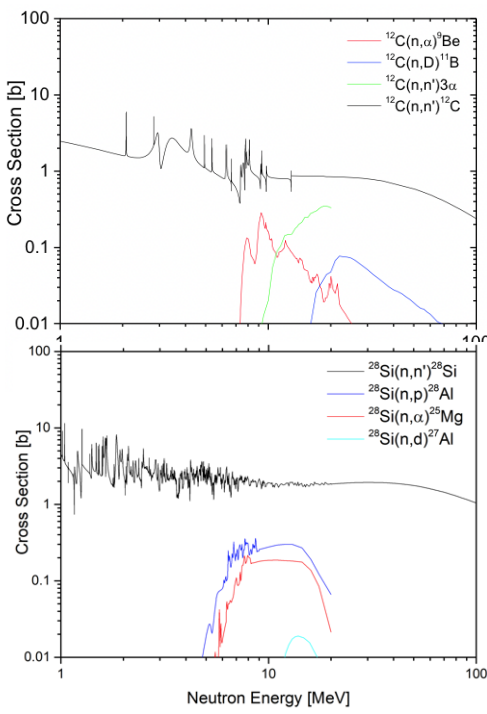
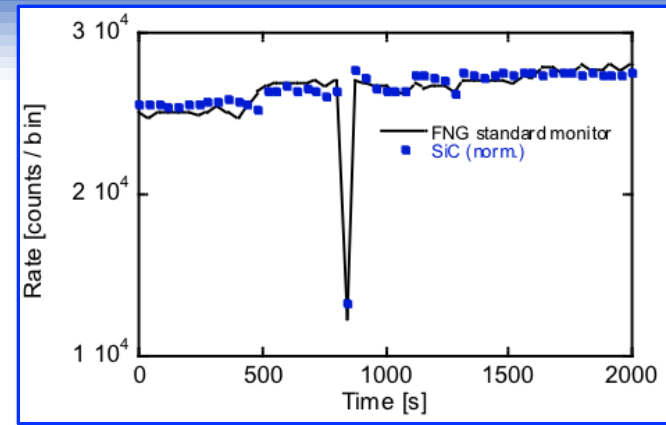


Performance overview : Neutrons detections

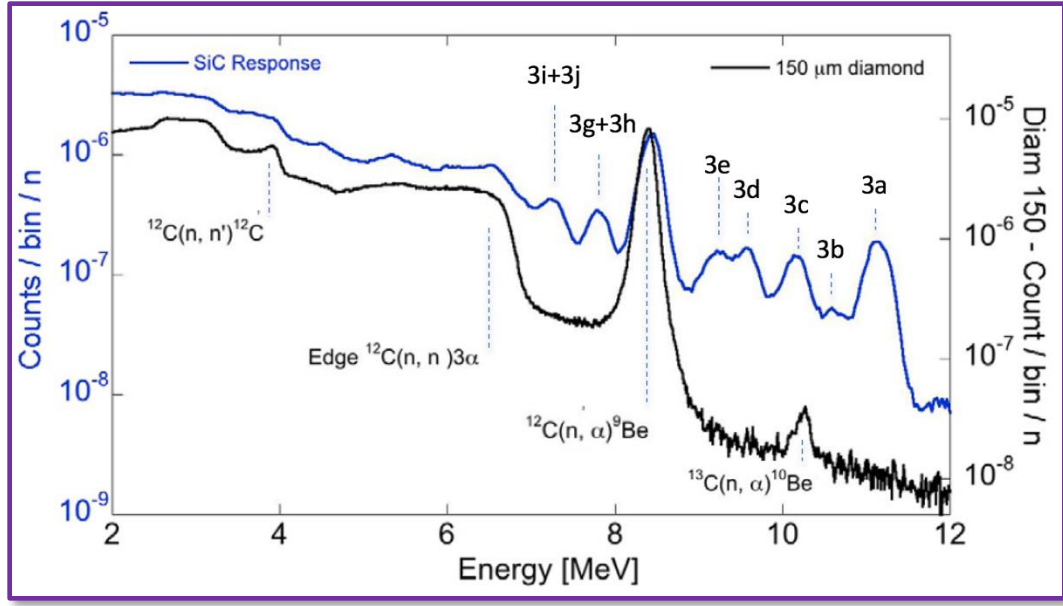
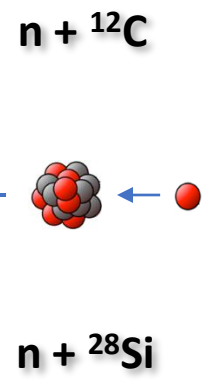
p-n diodes



SiC neutron Beam Monitor



Energy deposition



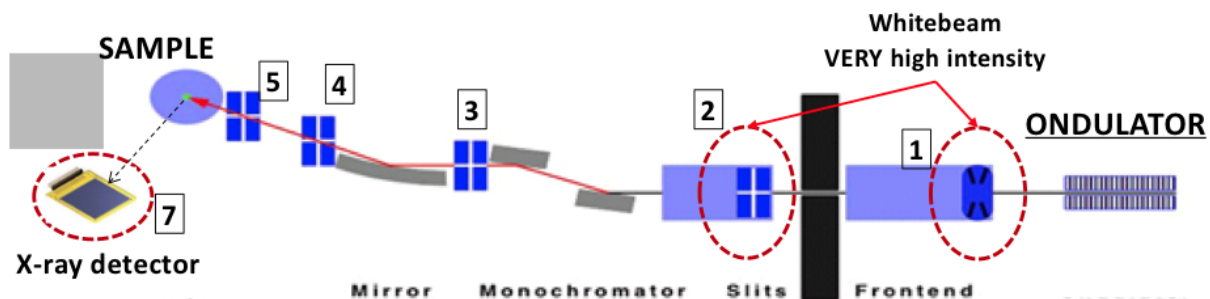
Absence of instabilities for 14 MeV neutron up to **$5 \cdot 10^{11}$ n/cm²**

Efficiency

Detector	Atomic/molecular density [cm ⁻³]	Efficiency measured for $E_d > 1.2$ MeV [and normalized per atom]	Efficiency measured in the $^{12}\text{C}(n,\alpha)^9\text{Be}$ peak
SCD 150 μm	$1.76 \cdot 10^{23}$	$(1.59 \pm 0.25) \cdot 10^{-3}$ [$2.97 \cdot 10^{-24}$]	$(0.91 \pm 0.15) \cdot 10^{-4}$
SiC 100 μm	$4.8 \cdot 10^{22}$	$(5.69 \pm 0.78) \cdot 10^{-4}$ [$4.74 \cdot 10^{-24}$]	$(2.02 \pm 0.30) \cdot 10^{-5}$

Performance overview : X-Ray detection

p-n diodes



Synchrotrons radiation

PAUL SCHERRER INSTITUT

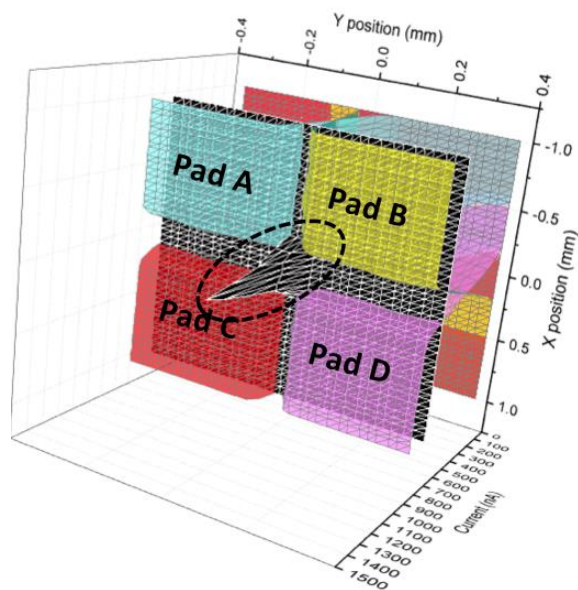


Beam Position Monitor (XBPM) { Transparency
Extreme radiation hardness
Fast response
1,2,3,4,5

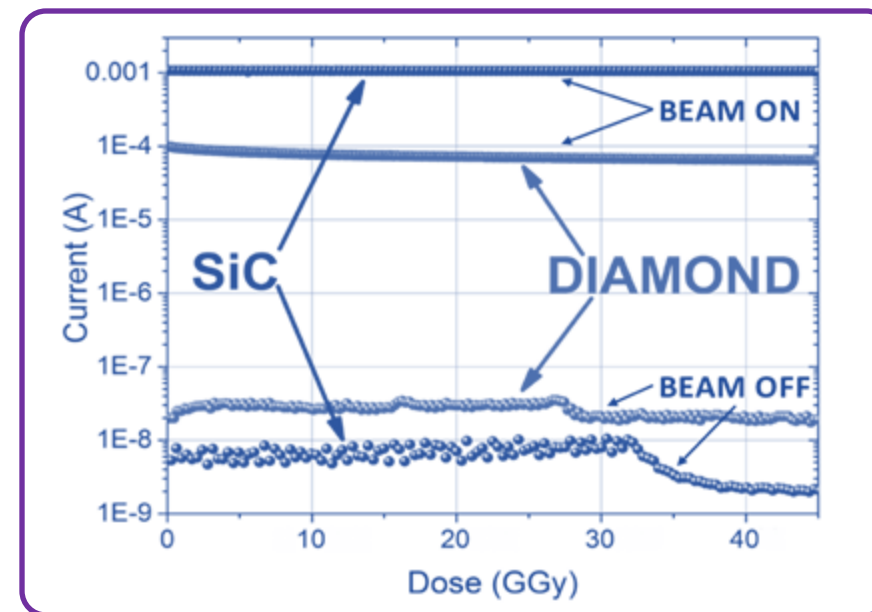
X-ray beam $10 \times 10 \mu\text{m}^2$, 5×10^{10} ph/sec @ 12.4keV



SiC 100 μm



Radiation hardness



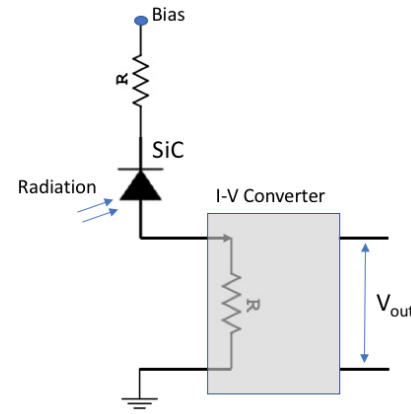
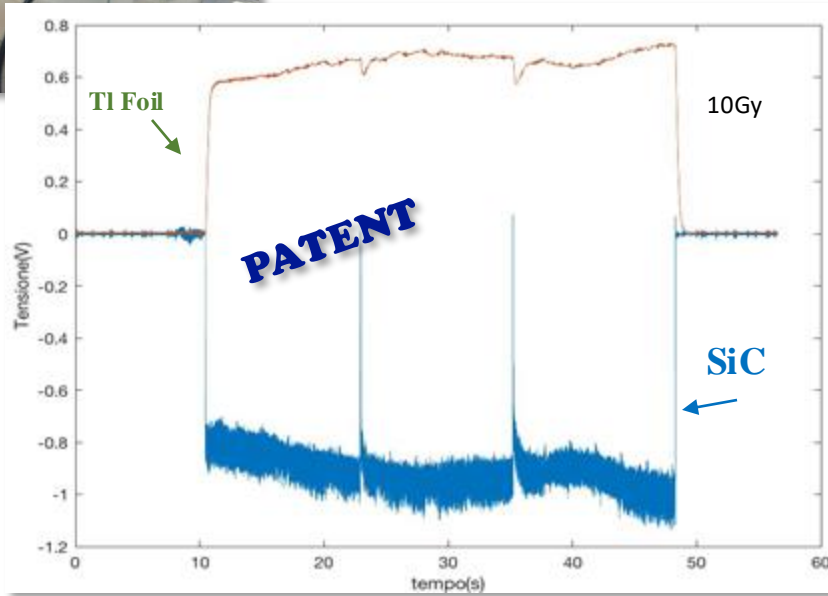
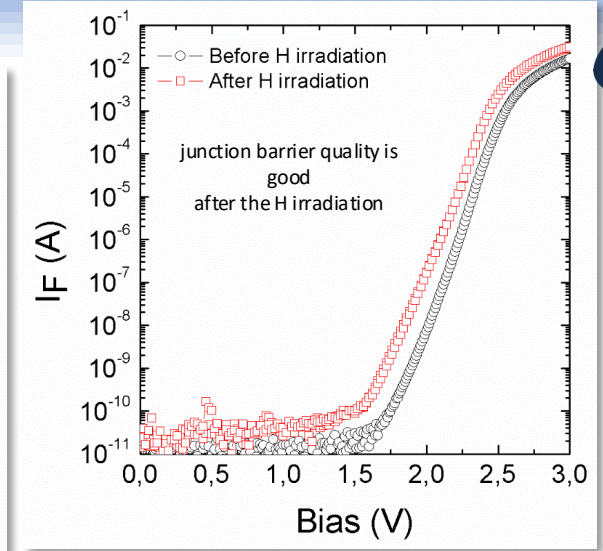
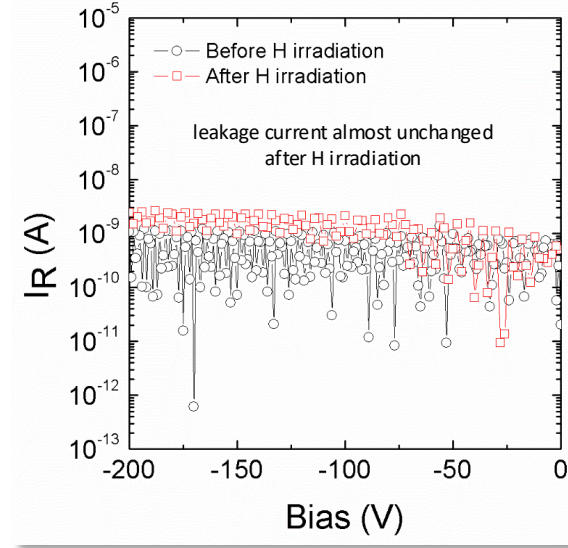
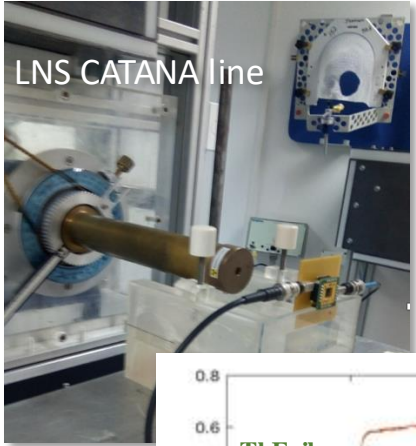
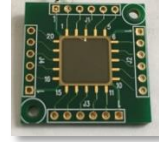
Radiation Hardness

Performance overview : Beam Monitoring

p-n diodes

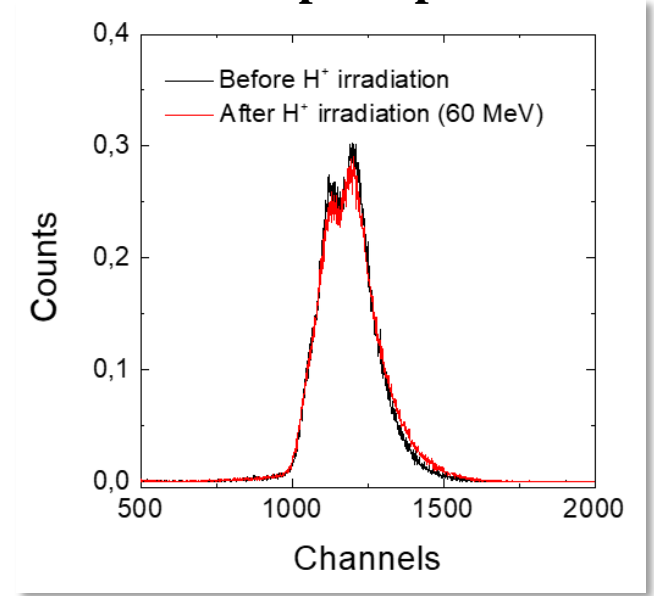
Protons beam

irradiation 60 MeV H^+ \rightarrow \square SiC $10 \mu\text{m } 1 \times 1 \text{ cm}^2$
 $5 \times 10^{13} \text{ H}^+/\text{cm}^2$ 3 kGy



Beam Monitor and dosimetry applications

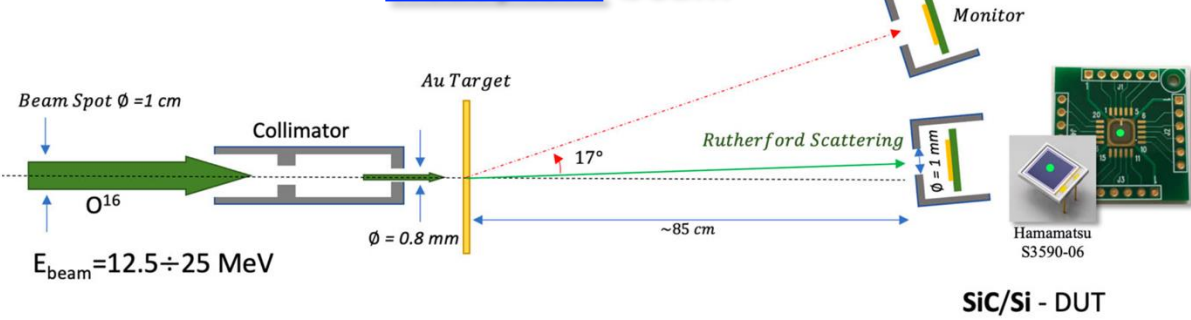
^{241}Am Alpha Spectrum



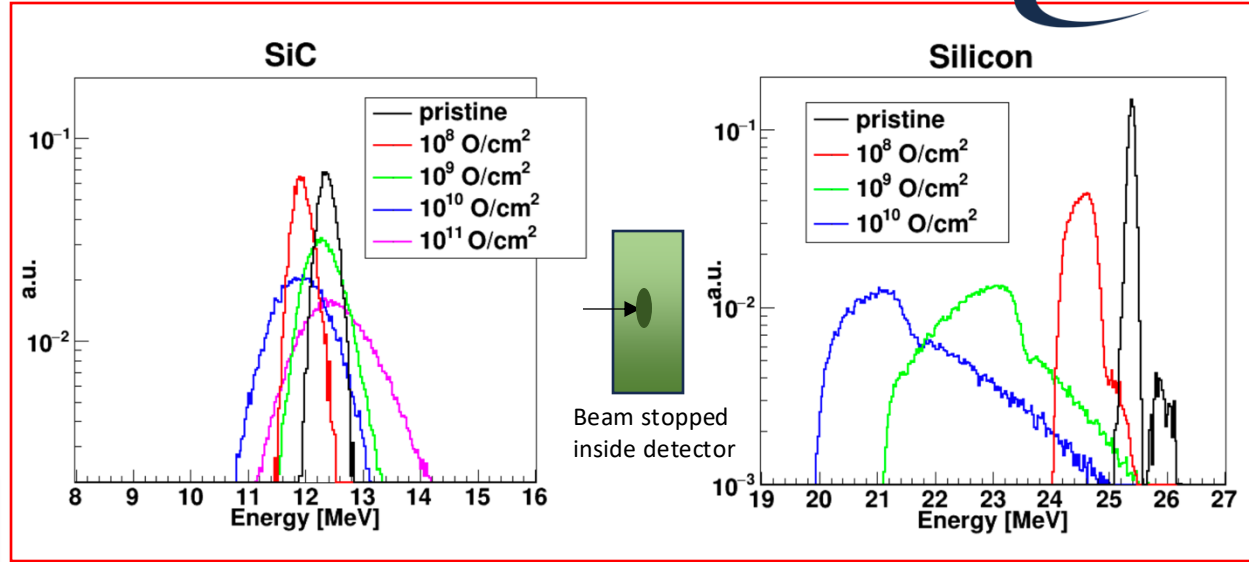
Performance overview: Radiation Hardness

p-n diodes

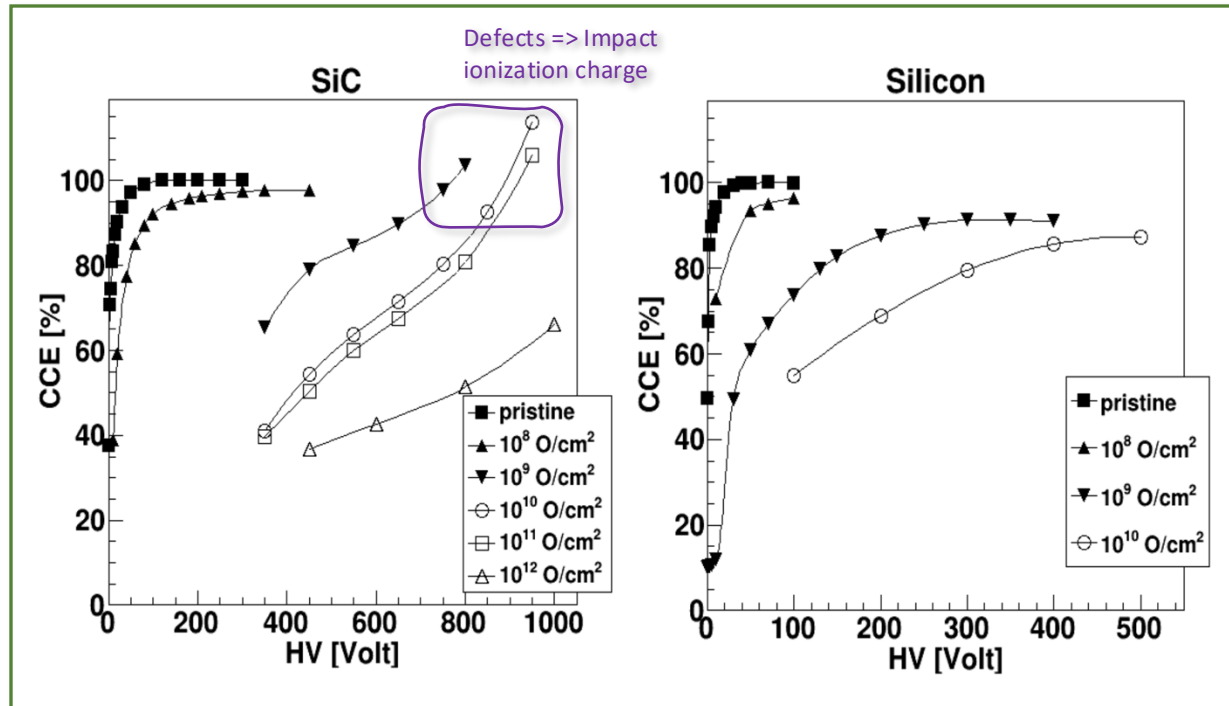
Heavy ions beam



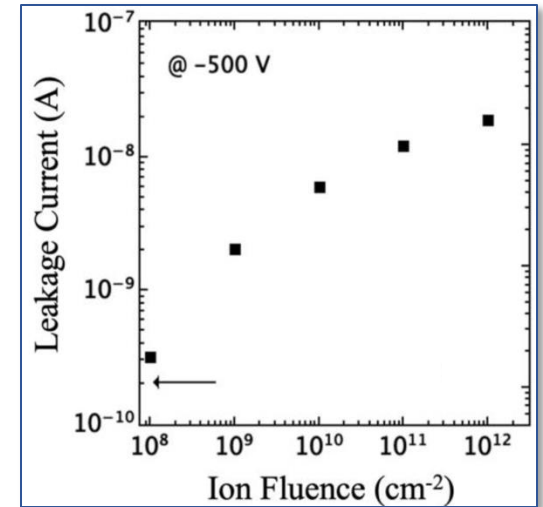
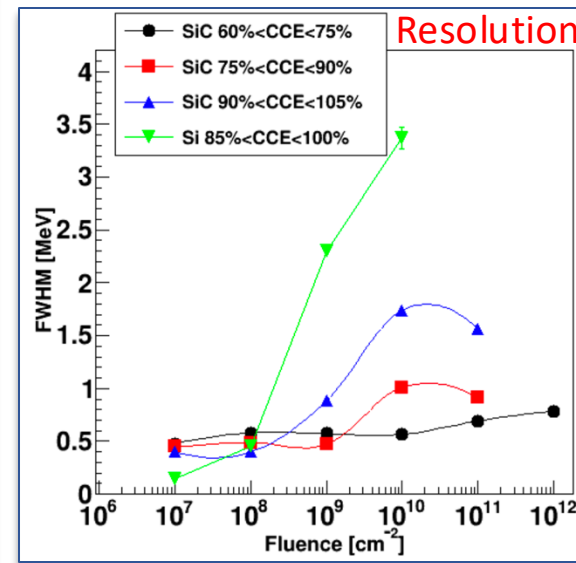
Energy spectra



Charge Collection Efficiency



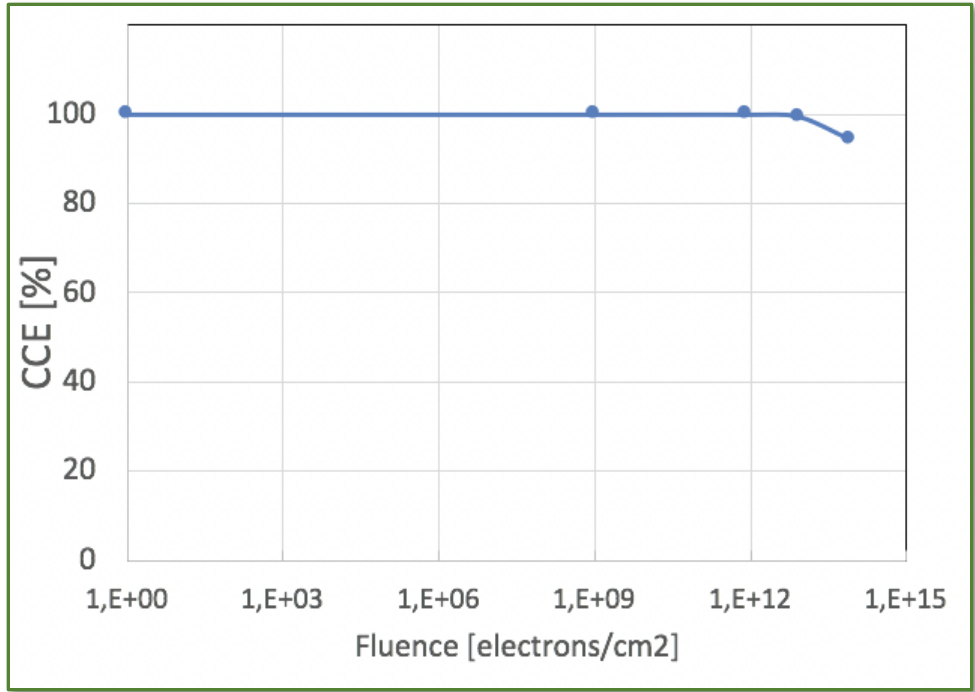
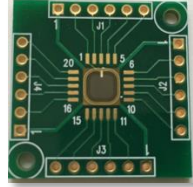
Resolution



Performance overview : Radiation Hardness

p-n diodes

electrons beam



LINAC @ UniMe

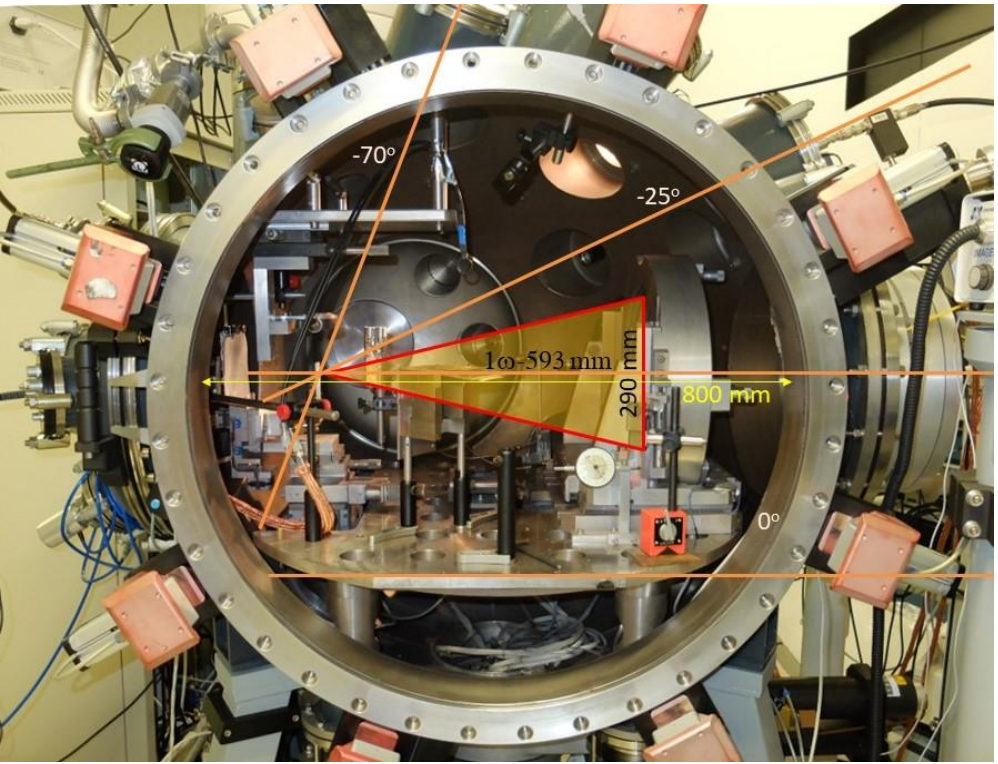
Electrons irradiation

- Energy 5 MeV
- Current 1-200 mA
- Rep. Rate 1-300 Hz
- Pulse duration 3 µsec

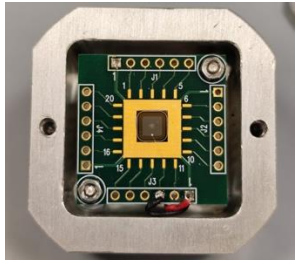
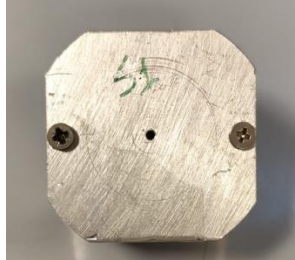
Electrons Beam Monitor



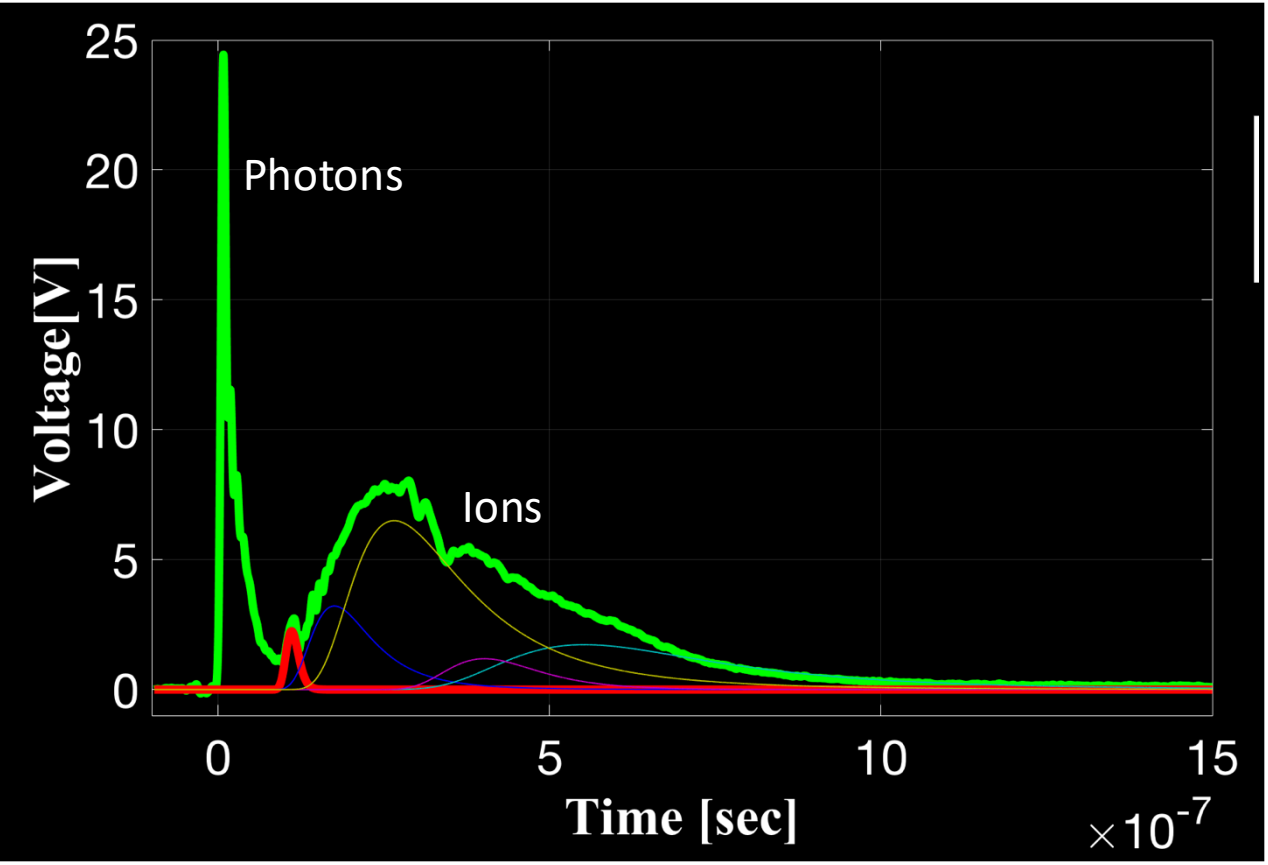
Performance overview : ToF measurements on Laser facility



PALS facility (Prague, CZ)



ToF - Spectrum



New set-up: NUMEM @ INFN-LNS



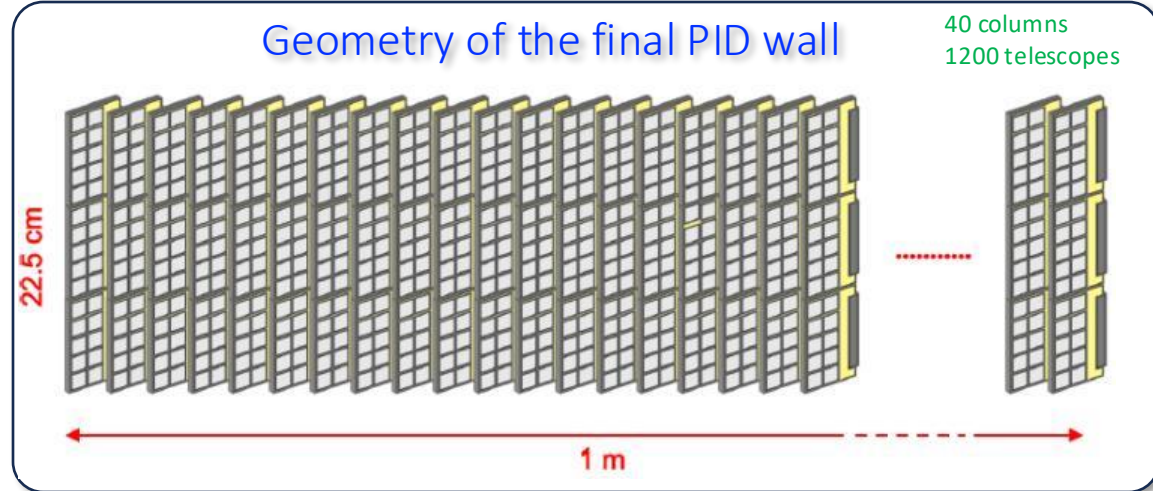
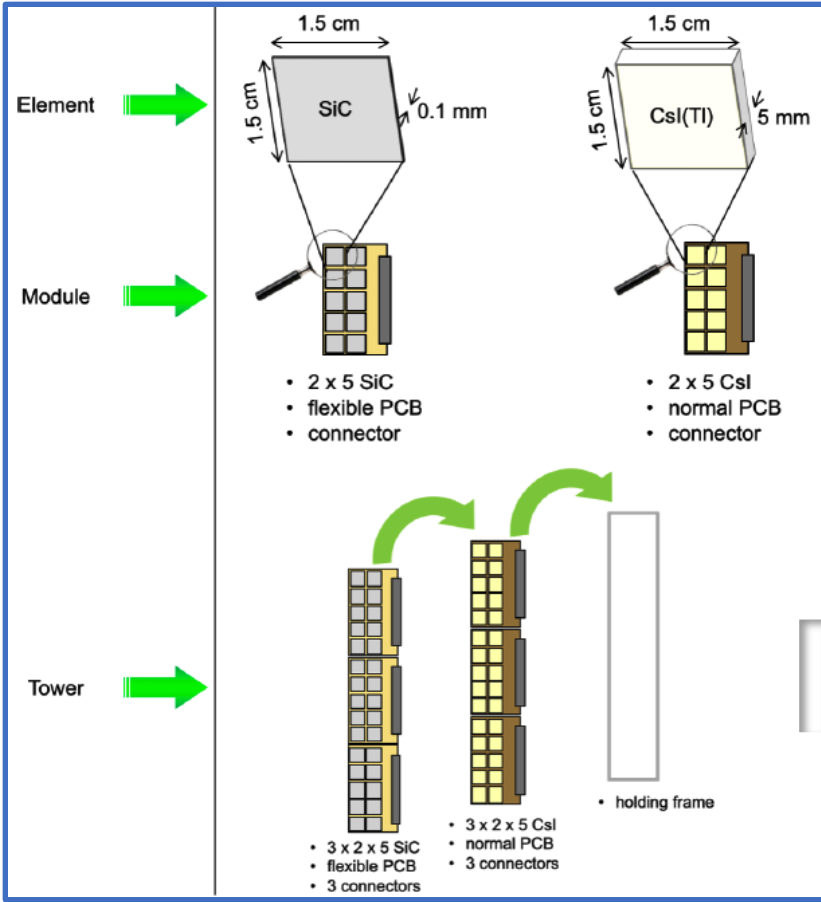
NUclear **M**atrix **E**lements of **N**eutrinoless Double Beta Decays by Heavy Ion **D**ouble **C**harge **E**xchange Reactions

MAGNEX – Magnetic spectrometer



- ❑ Small nuclear cross-sections
- ❑ High intensity ions beams

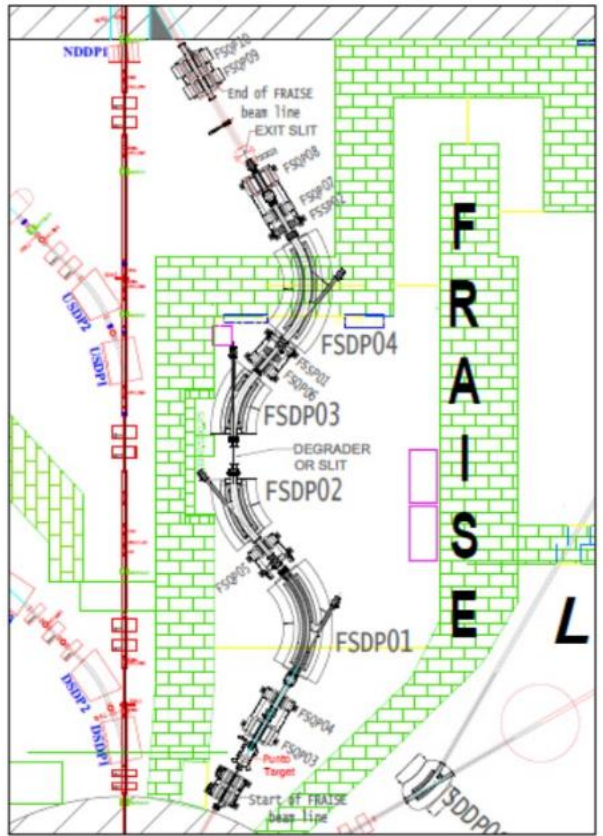
Focal plane detector



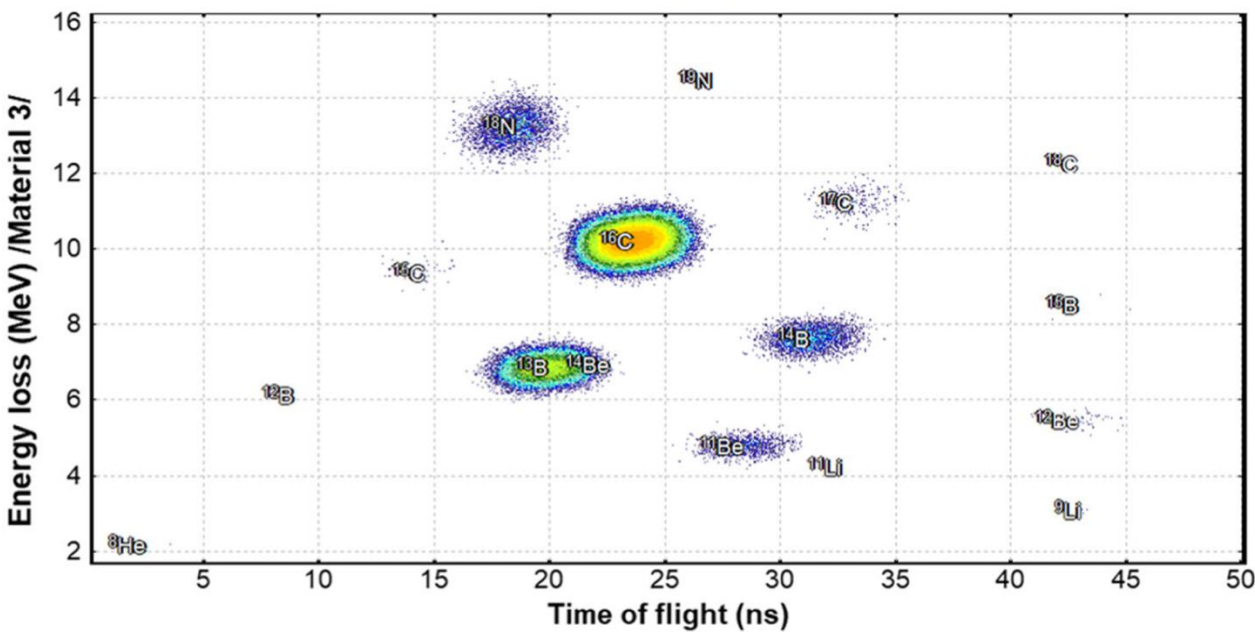
New set-up : FRAISE @ INFN



Will provide fragmentation beams with very high intensity (up to 10^7 p/s for ions like ^{16}C)



New fragment separator

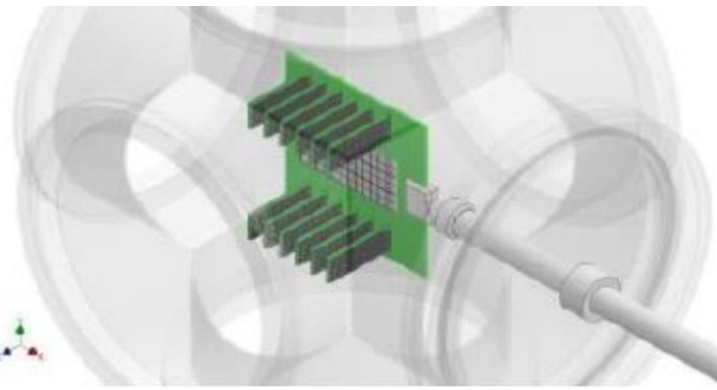


Most of the produced beams will be «cocktail» and need event by event identification through the measurement of time of flight and energy loss



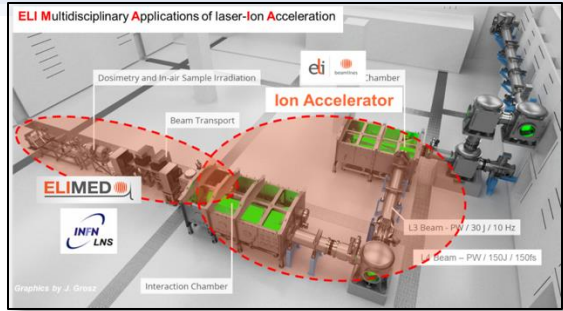
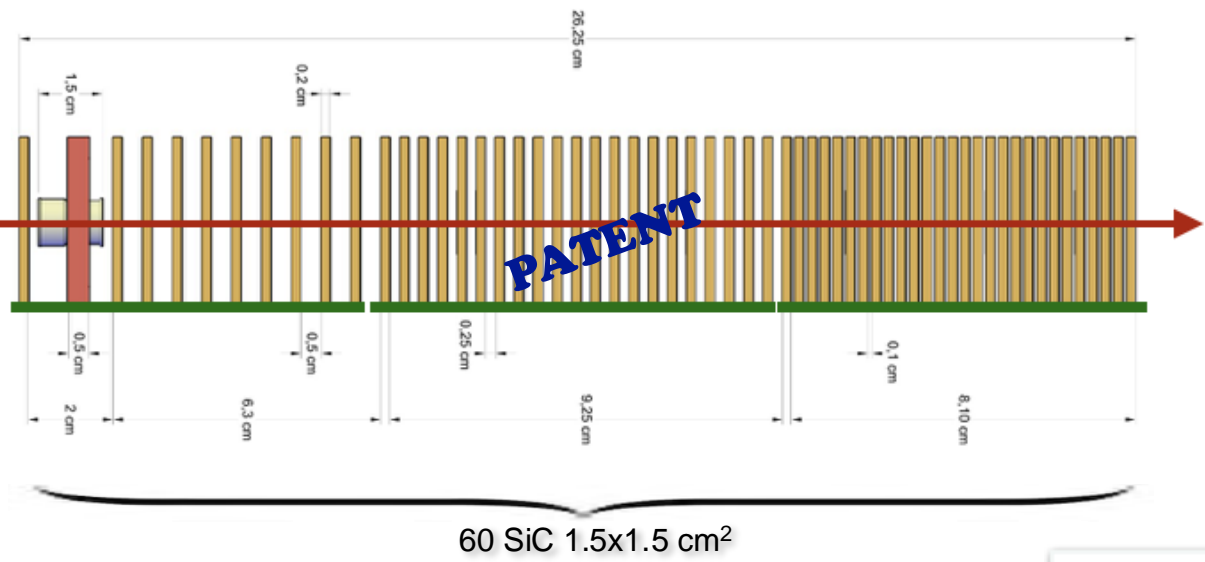
The new tagging device must be fast & radiation tolerant, therefore SiC was chosen as

One of the studied configuration foresees the use an array of pads of 5 mmx 5mm able to cover a surface up to 6 cmx 5cm



SiC New set-up: PRAGUE - Particle RANge measure Using Silicon Carbide

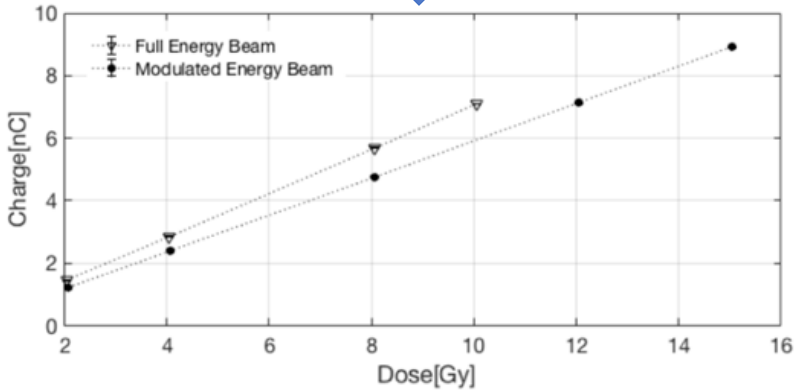
Incident proton



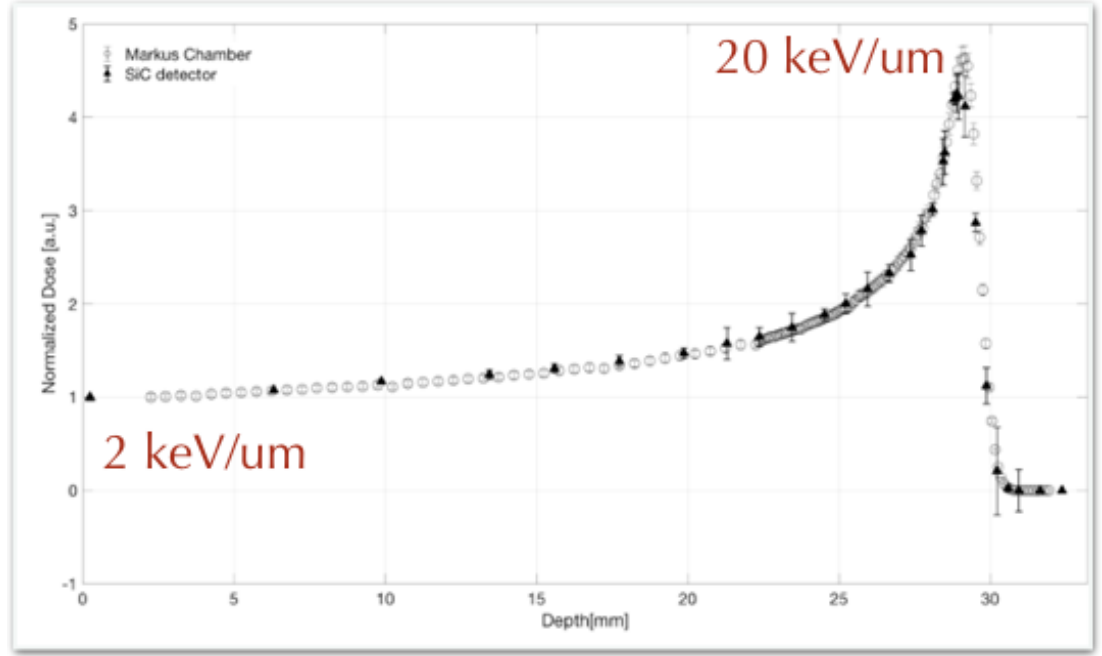
PRAGUE



Experiential test @CATANA Facility of LNS-INFN



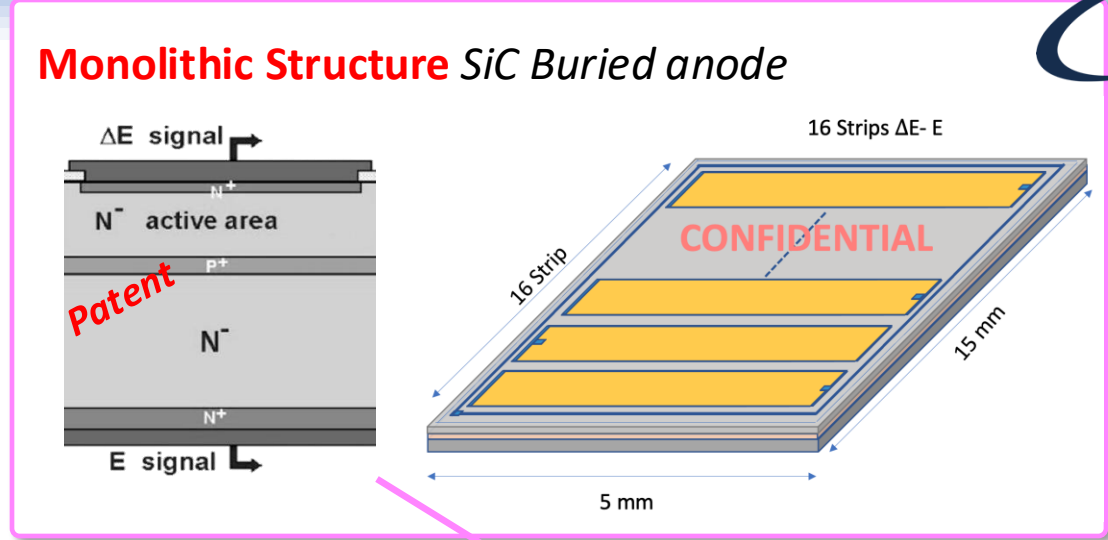
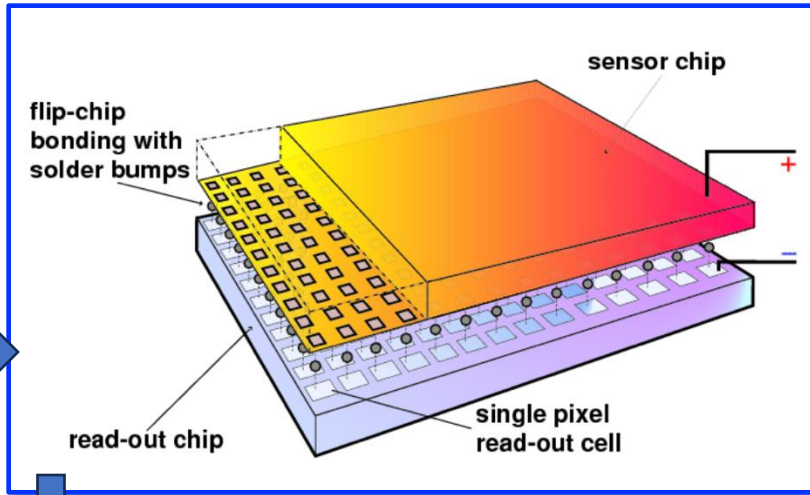
62 MeV proton beam, Modulated and Pristine beam, Beam Current: 10⁶-10⁸ p/cm²



Perspectives for **new** devices



TIMEPIX →



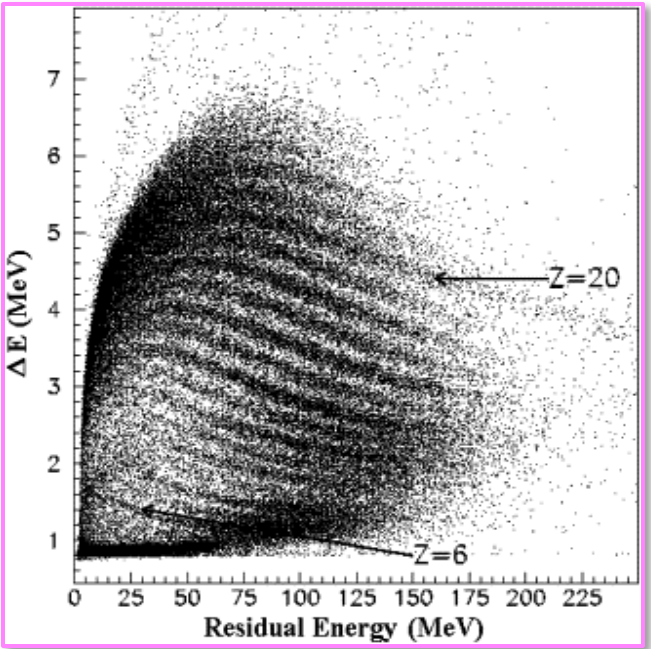
G. Cardella et al NIMA 378 (1996) 262
 S. Tudisco et al NIMA 426 (1999) 436
 F. Amorini et al NIMA 550 (2005) 248

SiC-Pixel detector

256x256 pixel

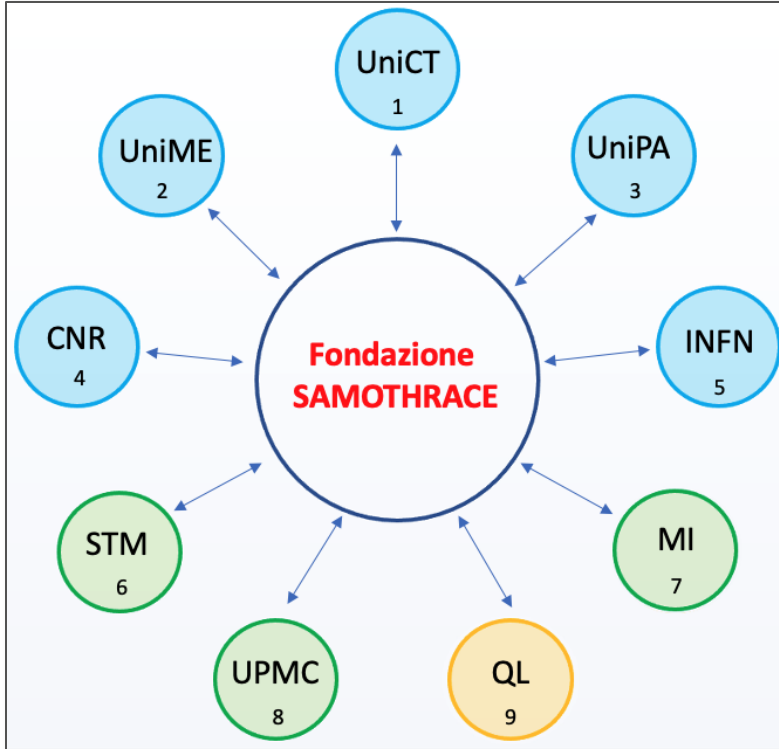
SiC-Strip Detector

15x15 mm²
 32 strip



PNRR - SAMOTHRACE R&D on Medical devices

SiciliAn MicroNanoTech Research And Innovation CEnter

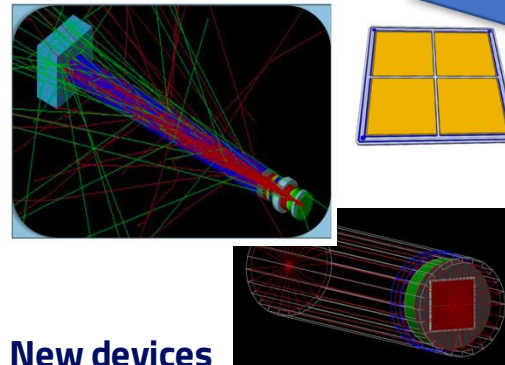


<https://samothrace.eu>



Wp4-SiC Detectors for particle therapy, dosimetry e micro-dosimetry

- **New SiC Radiation hard detectors** for: Particle therapy, dosimetry, beam monitoring, radio-protection
- **Micro-Dosimetry devices**
- **Imaging devices**



New devices

- ✓ Dosimeters
- ✓ Micro-dosimeters
- ✓ beam-monitors
- ✓ Imaging devices

Synergy
IMM-CNR, LPE, STM



Thanks for your attention !

